

N-Ch + P-Ch Fast Switching MOSFET
•General Description

The LH4012 uses trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. This device is suitable for high current load applications.

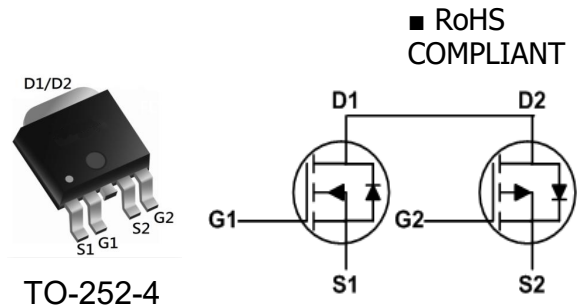
BVDSS	$R_{DS(on)}$	ID
40	19	30
-40	34	-20

•Features

- Advance high cell density trench technology
- Low $R_{DS(on)}$ to minimize conductive loss
- Low Gate Charge for fast switching

•Application

- Lighting
- Power Supplies


•Ordering Information:

Part Number	LH4012
Package	TO-252-4
Basic Ordering Unit (pcs)	2500
Normal Package Material Ordering Code	LH4012T7-TO252-4-TAP
Halogen Free Ordering Code	LH4012T7-TO252-4-TAP-HF

•Absolute Maximum Ratings (TC =25°C)

PARAMETER	SYMBOL	Value		UNIT
		N-Ch	P-Ch	
Drain-Source Breakdown Voltage	BV_{DSS}	40	-40	V
Gate-Source Voltage	V_{GS}	±20	±20	V
Continuous Drain Current , $T_C = 25^{\circ}C^1$	I_D	30	-20	A
Continuous Drain Current , $T_C = 100^{\circ}C^1$	I_D	18	-16	A
Pulsed drain current (TC = 25°C, tp limited by Tjmax) ²	I_{DM}	46	-40	A
Single Pulse Avalanche Energy ³	E_{AS}	28	66	mJ
Power Dissipation ⁴	$P_D(T_C=25^{\circ}C)$	25	31.3	W
Operating Temperature	T_J	-55~+150	-55~+150	°C
Storage Temperature	T_{STG}	-55~+150	-55~+150	°C

●N-Channel Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	40	--	--	V
BVDSS Temperature Coefficient	$\Delta BV_{DSS}/\Delta T_J$	Reference to 25°C, $I_D=1mA$	--	0.034	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.5	2.5	V
$V_{GS(TH)}$ Temperature Coefficient	$\Delta V_{GS(TH)}$		--	-4.56	--	V
Drain-source On Resistance ²	$R_{DS(ON)}$	$V_{GS}=10V, I_D=12A$	--	19	25	mΩ
		$V_{GS}=4.5V, I_D=10A$	--	24	35	
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=32V, V_{GS}=0V, T_J=25^\circ C$	--	--	1	uA
		$V_{DS}=32V, V_{GS}=0V, T_J=55^\circ C$	--	--	5	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	--	--	±100	nA
Forward Transconductance	G_{FS}	$V_{DS}=5V, I_D=12A$	--	8	--	S
Gate Resistance	R_g	$V_{DS}=0V, V_{GS}=0V, f=1MHz$	--	2.6	5.2	Ω
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=15V, f=1.0MHz$	--	593	--	pF
Output Capacitance	C_{oss}		--	76	--	
Reverse transfer Capacitance	C_{rss}		--	56	--	
Turn-On Delay Time	$T_{d(on)}$	$V_{DD}=20V, V_{GS}=10V, R_G=3.3\Omega, I_D=1A$	--	8.9	--	nS
Turn-Off Delay Time	$T_{d(off)}$		--	41	--	
Turn-On Rise Time	T_r		--	2.2	--	
Turn-Off Fall Time	T_f		--	2.7	--	
Total Gate Charge	Q_g	$I_D=12A, V_{DS}=20V, V_{GS}=4.5V$	--	5.5	---	nC
Gate-to-Source Charge	Q_{gs}		--	1.25	--	
Gate-to-Drain Charge	Q_{gd}		--	2.5	---	
Continuous Diode Forward Current ^{1,5}	I_S	$V_{GS}=V_{DS}=0V, \text{Force Current}$	--	--	23	A
Pulsed Diode Forward Current ^{2,5}	I_{SM}		--	--	46	A
Diode Forward Voltage ²	V_{SD}	$T_J=25^\circ C, I_S=-20A, V_{GS}=0V$	--	--	1.2	V

Notes:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper;
- 2.The data tested by Pulsed,Pulse width ≤ 300μs, Duty cycle ≤ 2%;
- 3.The EAS data shows Max. rating.The Test condition is L=0.1mH, $I_{AS}=17.8A, V_{DD}=25V, V_{GS}=10V$;
- 4.The Power Dissipation is limited by 150°C junction temperature;
- 5.The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

●P-Channel Typical Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=-250\mu A$	-40	--	--	V
BVDSS Temperature Coefficient	$\Delta BV_{DSS}/\Delta T_J$	Reference to 25°C, $I_D=-1mA$	--	0.012	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1.0	-1.5	-2.5	V
$V_{GS(TH)}$ Temperature Coefficient	$\Delta V_{GS(TH)}$		--	-4.32	--	V
Drain-source On Resistance ²	$R_{DS(ON)}$	$V_{GS}=-10V, I_D=-8A$	--	34	40	mΩ
		$V_{GS}=-4.5V, I_D=-5A$	--	47	65	
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=-32V, V_{GS}=0V, T_J=25^\circ C$	--	--	1	uA
		$V_{DS}=-32V, V_{GS}=0V, T_J=55^\circ C$	--	--	5	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	--	--	±100	nA
Forward Transconductance	G_{FS}	$V_{DS}=-5V, I_D=-8A$	--	12.6	--	S
Gate Resistance	R_g	$V_{DS}=0V, V_{GS}=0V, f=1MHz$	--	13	16	Ω
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=-15V, f=1.0MHz$	--	1004	--	pF
Output Capacitance	C_{oss}		--	108	--	
Reverse transfer Capacitance	C_{rss}		--	80	--	
Turn-On Delay Time	$T_{d(on)}$	$V_{DD}=-15V, V_{GS}=-10V, R_G=3.3\Omega, I_D=1A$	--	19.2	--	nS
Turn-Off Delay Time	$T_{d(off)}$		--	48.6	--	
Turn-On Rise Time	T_r		--	12.8	--	
Turn-Off Fall Time	T_f		--	4.6	--	
Total Gate Charge	Q_g	$I_D=-12A, V_{DS}=-20V, V_{GS}=-4.5V$	--	9	---	nC
Gate-to-Source Charge	Q_{gs}		--	2.54	--	
Gate-to-Drain Charge	Q_{gd}		--	3.1	---	
Continuous Diode Forward Current ^{1,5}	I_S	$V_{GS}=V_{DS}=0V, \text{Force Current}$	--	--	-20	A
Pulsed Diode Forward Current ^{2,5}	I_{SM}		--	--	-40	A
Diode Forward Voltage ²	V_{SD}	$T_J=25^\circ C, I_S=-1A, V_{GS}=0V$	--	--	-1.2	V

●Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case ¹	R_{thJC}	5	°C/W
Thermal Resistance Junction-ambient ¹	R_{thJA}	62	°C/W

Notes:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper;
- 2.The data tested by Pulsed,Pulse width ≤ 300μs, Duty cycle ≤ 2%;
- 3.The EAS data shows Max. rating.The Test condition is L=0.1mH, $I_{AS}=-20A, V_{DD}=-25V, V_{GS}=-10V$;
- 4.The Power Dissipation is limited by 150°C junction temperature;
- 5.The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

●N-Ch Typical Characteristics

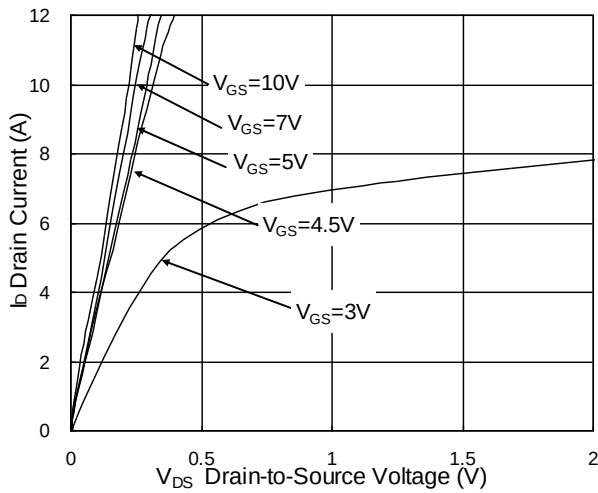


Fig.1 Typical Output Characteristics

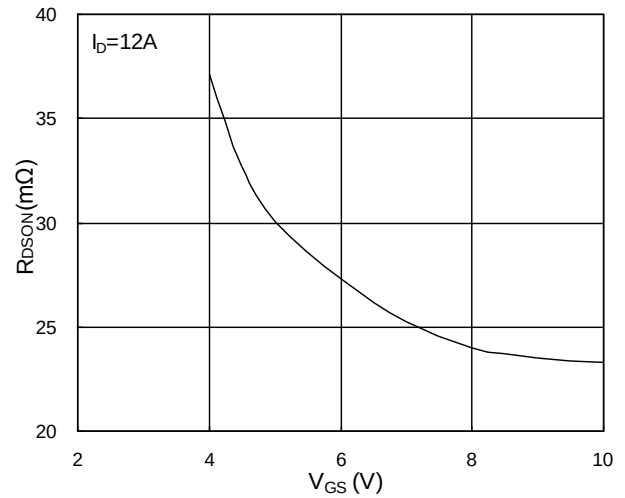


Fig.2 On-Resistance vs. G-S Voltage

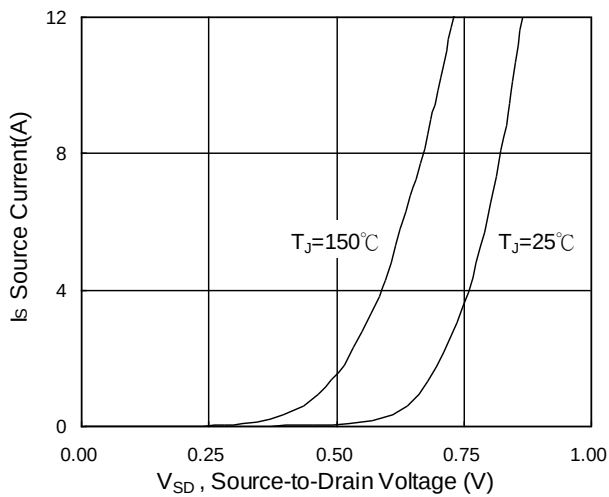


Fig.3 Forward Characteristics of Reverse

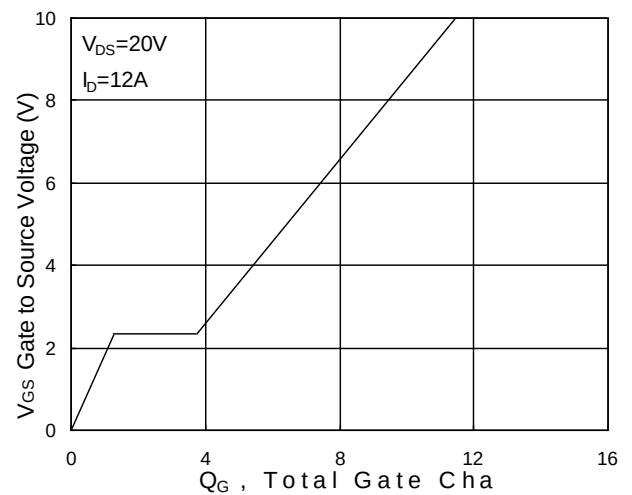


Fig.4 Gate-Charge Characteristics

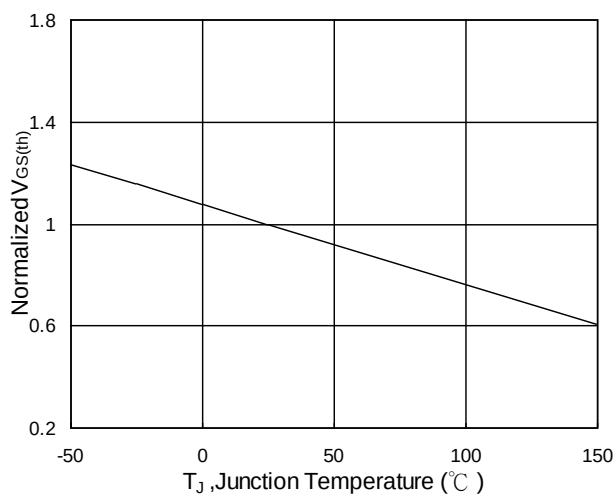


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

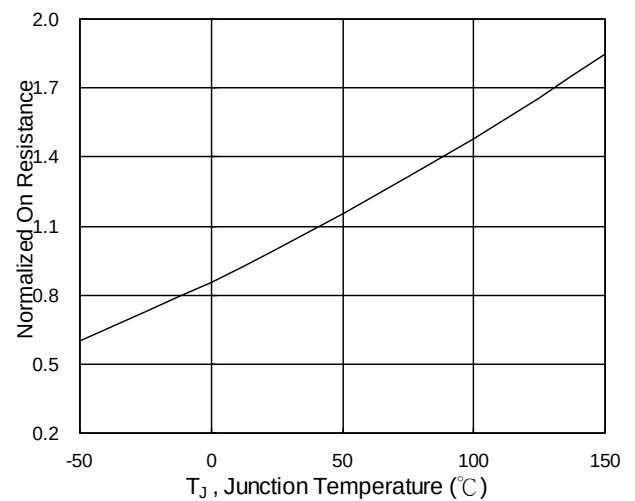


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

●N-Ch Typical Characteristics(Cont.)

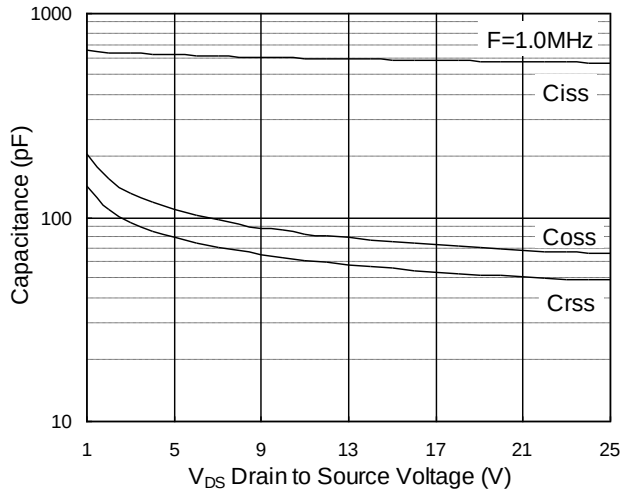


Fig.7 Capacitance

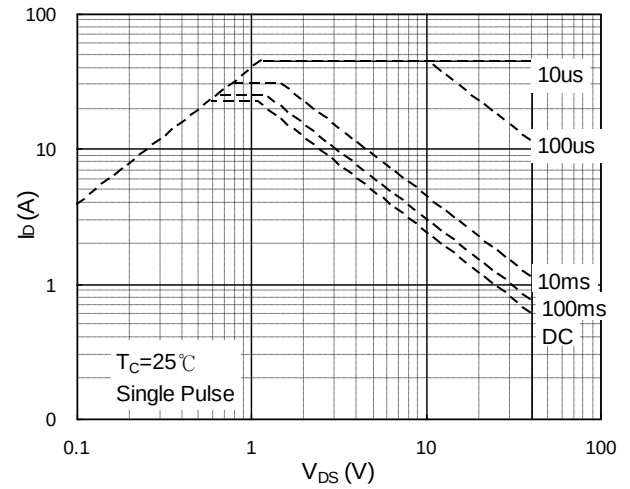


Fig.8 Safe Operating Area

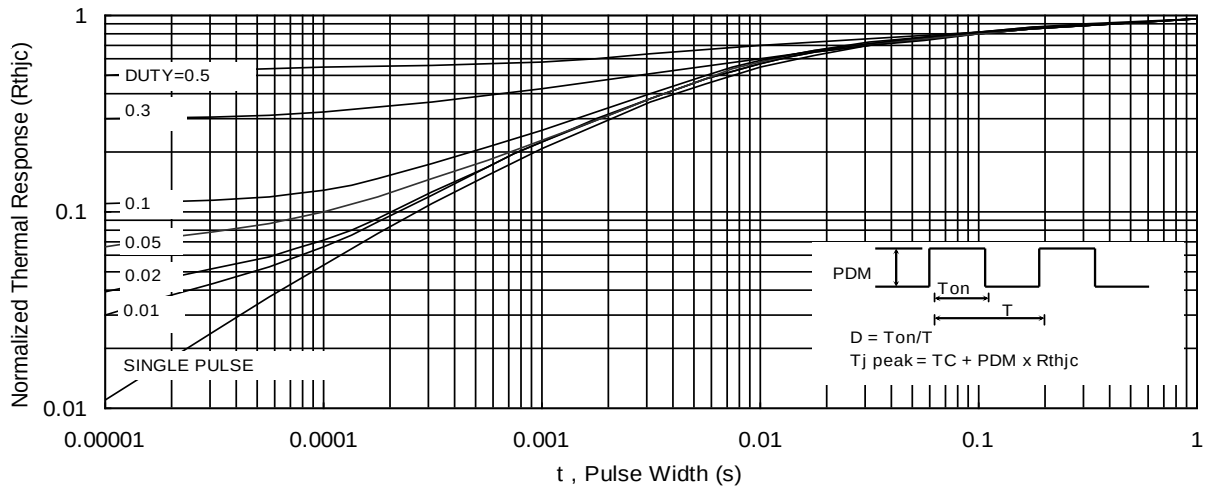


Fig.9 Normalized Maximum Transient Thermal Impedance

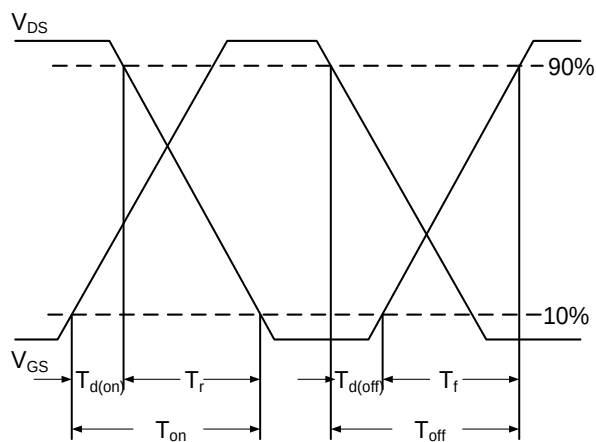


Fig.10 Switching Time Waveform

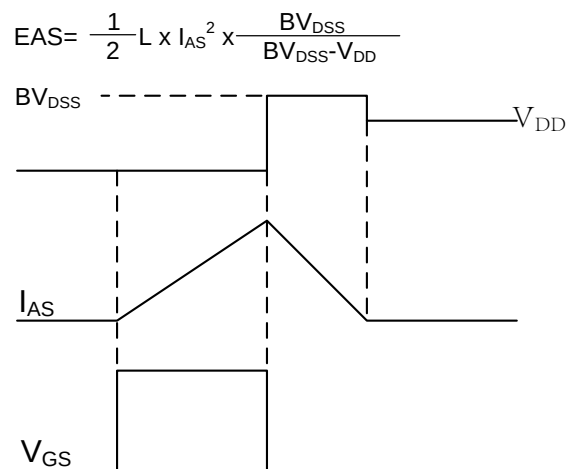


Fig.11 Unclamped Inductive Switching Wave

● **P-Channel Typical Characteristics**

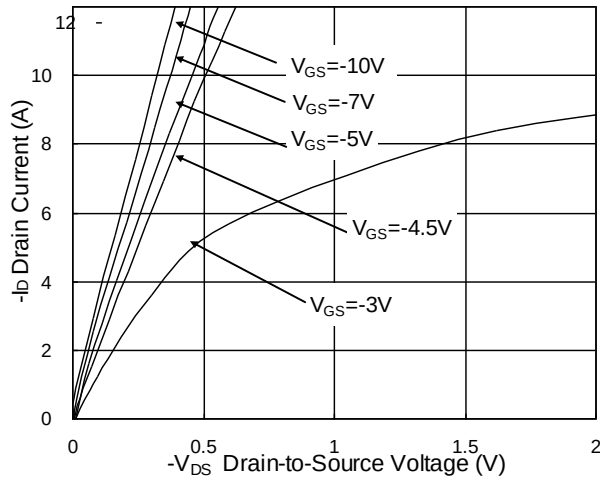


Fig.1 Typical Output Characteristics

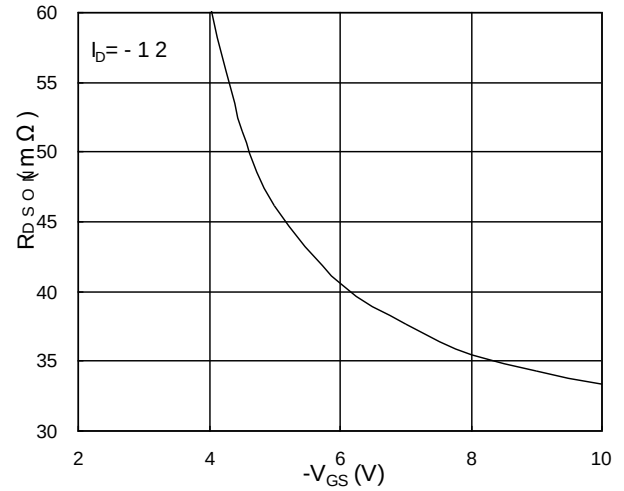


Fig.2 On-Resistance v.s Gate-Source

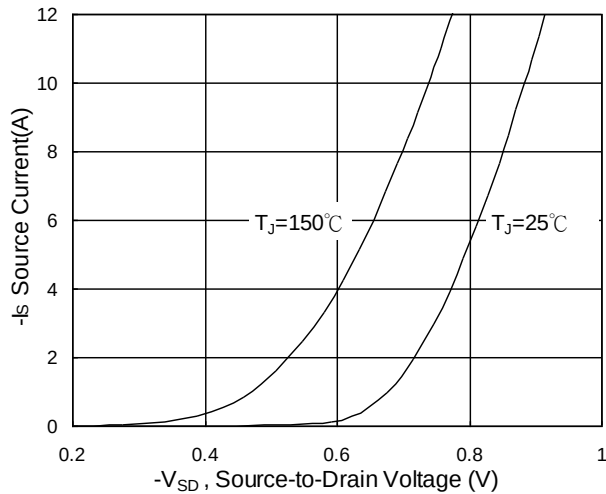


Fig.3 Forward Characteristics of Reverse

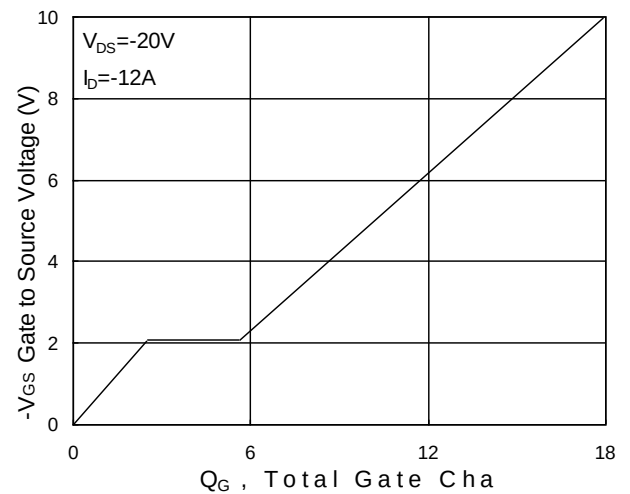


Fig.4 Gate-Charge Characteristics

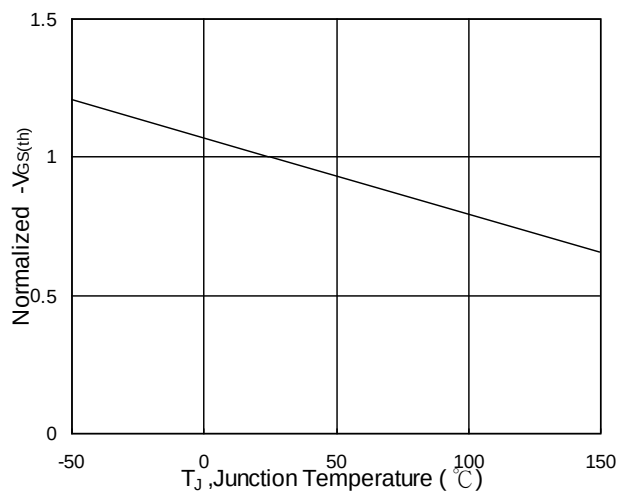


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

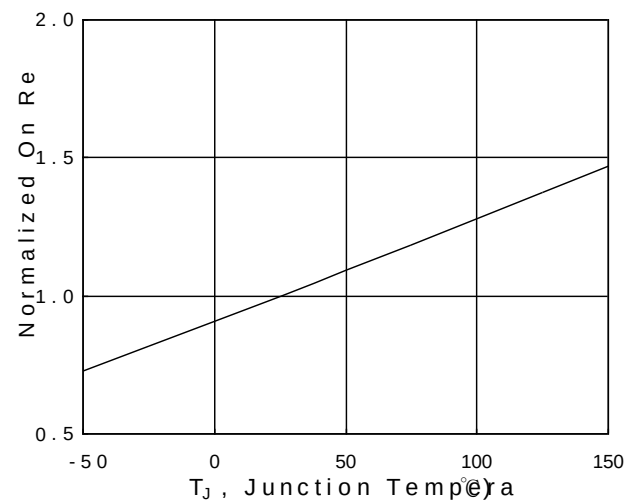


Fig.6 Normalized $R_{DS(on)}$ v.s T_J

● **P-Channel Typical Characteristics(cont.)**

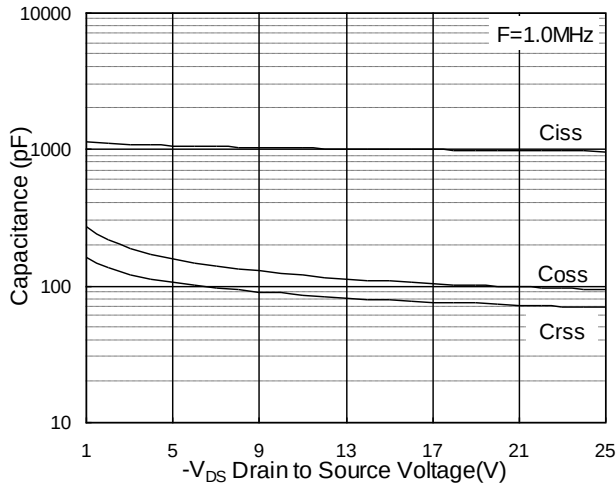


Fig.7 Capacitance

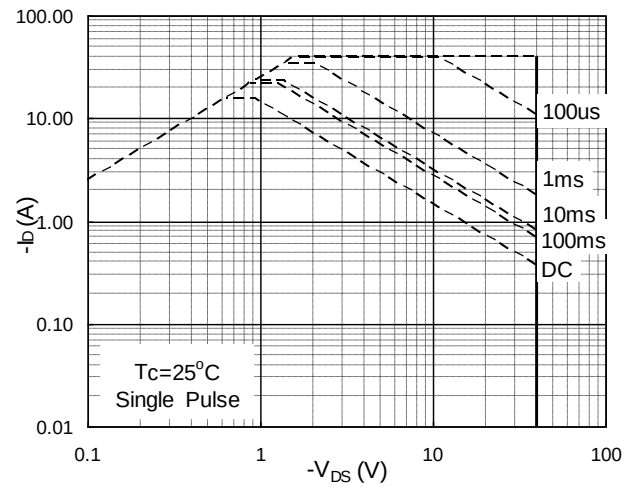


Fig.8 Safe Operating Area

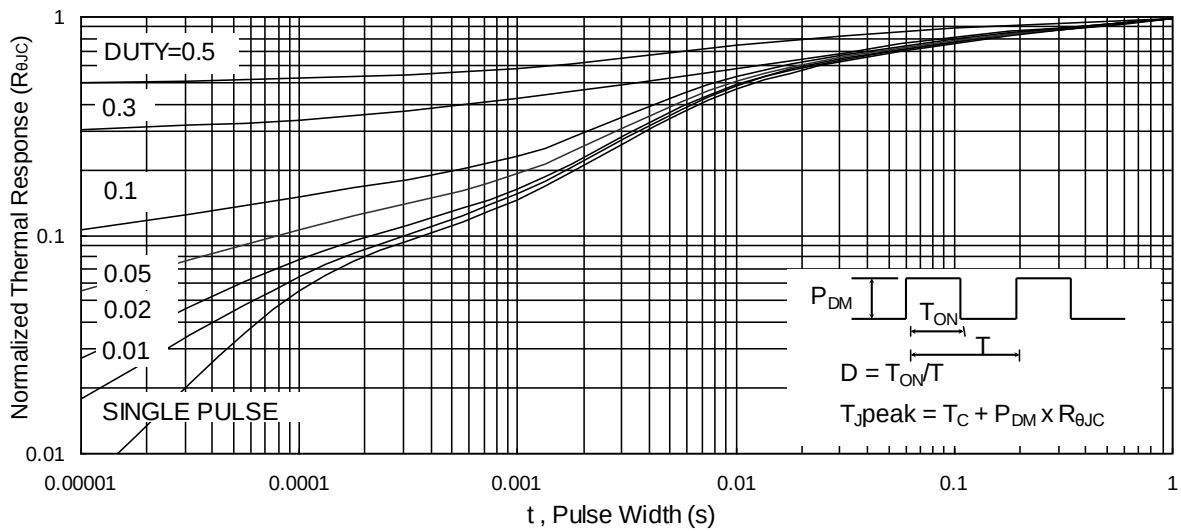


Fig.9 Normalized Maximum Transient Thermal Impedance

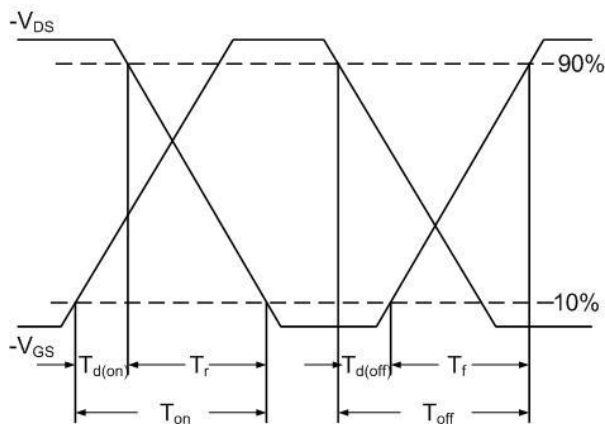


Fig.10 Switching Time Waveform

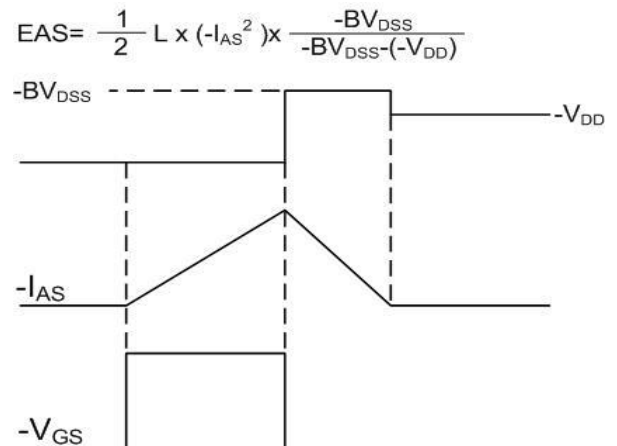


Fig.11 Unclamped Inductive Waveform